

**Search Notes****Application/Control No.**

10/591,132

**Examiner**

Mathieu D. Vargot

**Applicant(s)/Patent under  
Reexamination**

SAWAISHI ET AL.

**Art Unit**

1791

**SEARCHED**

Class	Subclass	Date	Examiner
264	1.33, 106, 107, 328.1		
425	810, 542		
425	193, 385	9/24/2009	MDV

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR